Support information

## Light and Heat Triggering Modulation of the Electronic Performance of a Graphdiyne-based Thin Film Transistor

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Figure S5-S7 Electric field regulation field effect transistor performance under fixed irradiation wavelength and intensity.

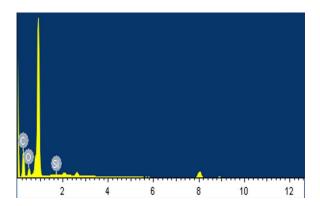


Figure S1 EDS analysis of the content of each element of GDY film.

element	Weight (percent)	atom (percent)
СК	59.94	66.86
ОК	38.93	32.60
Si K	1.13	0.54
total	100.00	100.00

**Table S1** The proportion of elemental and atomic content of GDY film.

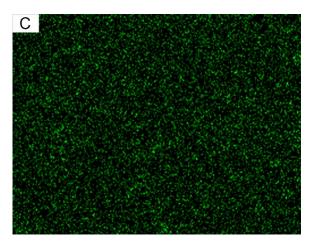


Figure S2 C element mapping of GDY film.

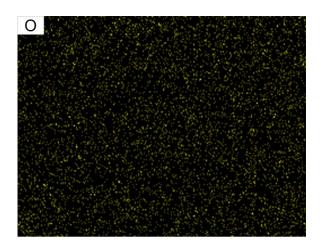


Figure S3 O element mapping of GDY film.

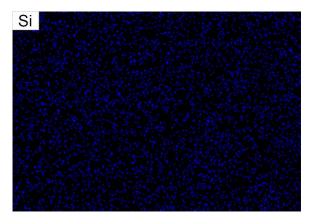
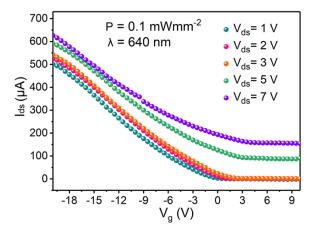
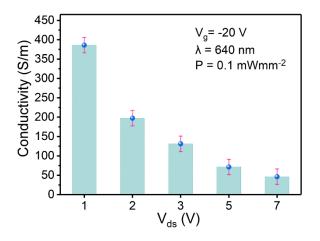


Figure S4 Si element mapping of GDY film.



**Figure S5** Transfer characteristics of different  $V_{ds}$  under fixed wavelength (640 nm) and intensity illumination (0.1mWmm<sup>-2</sup>).



**Figure S6** Conductivity of different  $V_{ds}$  under fixed wavelength (640 nm) and intensity irradiation (0.1mWmm<sup>-2</sup>).

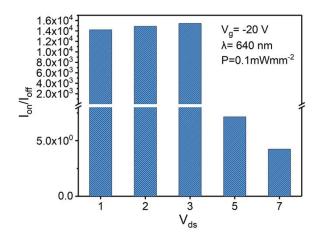


Figure S7 The on/off ratio of different  $V_{ds}$  under fixed wavelength (640 nm) and intensity irradiation (0.1mWmm<sup>-2</sup>).